USOOD346122S

United States Patent [19]

Nightingale et al.

[11] **Patent Number: Des. 346,122**

[45] **Date of Patent: ** Apr. 19, 1994**

---

[54] **PROBING HEAD FOR AN ELECTRICAL TEST PROBE**

[75] Inventors: **Mark W. Nightingale**, Washougal, Wash.; **Jonathan E. Myers**, Aloha, Oreg.

[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[**] Term: **14 Years**

[21] Appl. No.: **5,282**

[22] Filed: **Mar. 1, 1993**

[52] **U.S. Cl.** **D10/78**

[58] **Field of Search** .... 324/72.5, 158 P; D10/78

[56] **References Cited**

U.S. PATENT DOCUMENTS

4,978,921	12/1990	Indiz et al.	324/72.5 X
5,032,787	7/1991	Johnston et al.	324/72.5 X
5,041,781	8/1991	Kawada et al.	324/72.5 X

OTHER PUBLICATIONS

Tektronix, Passive Voltage Probes, ©1990, p.411, provided by applicant.

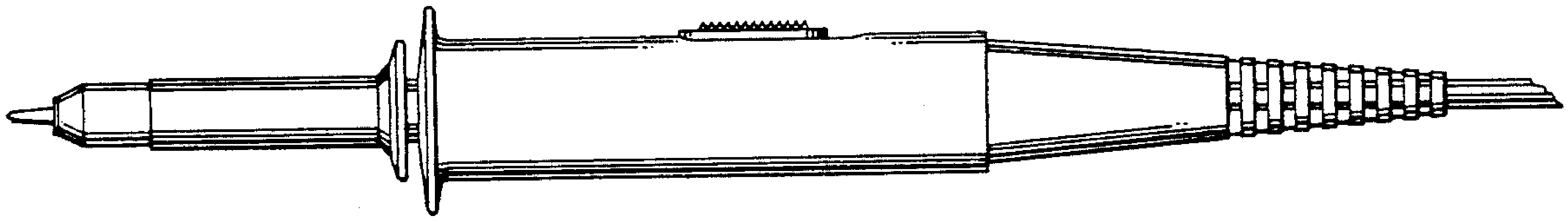
Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis
Attorney, Agent, or Firm—William K. Bucher

[57] **CLAIM**

The ornamental design for a probing head for an electrical test probe, as shown and described.

DESCRIPTION

FIG. **1** is a left side elevation view of the probing head for an electrical test probe showing our new design;
FIG. **2** is a right side elevation view thereof;
FIG. **3** is a top plan view thereof;
FIG. **4** is a bottom plan view thereof;
FIG. **5** is a front elevation view thereof; and,
FIG. **6** is a rear elevation view thereof.
The cord member has been broken away indicating an indeterminate length.



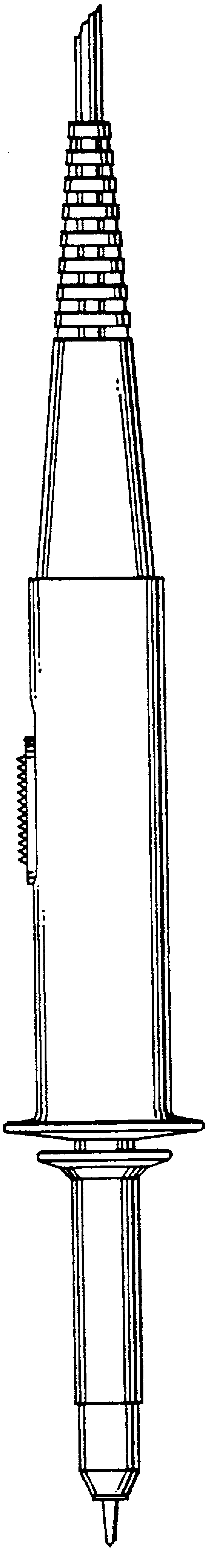


Fig.1

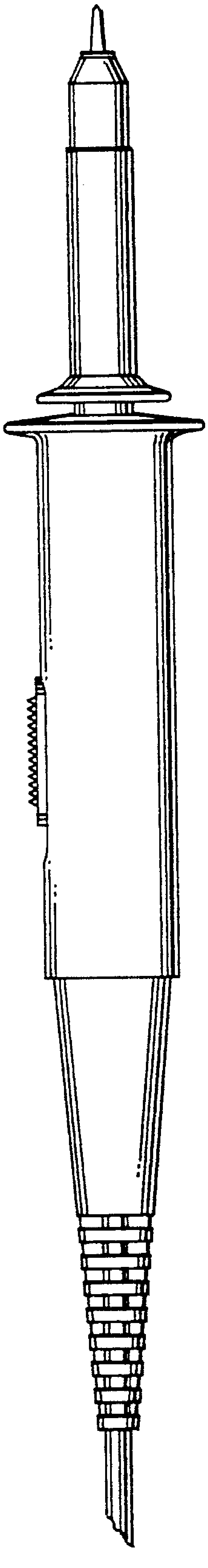


Fig.2

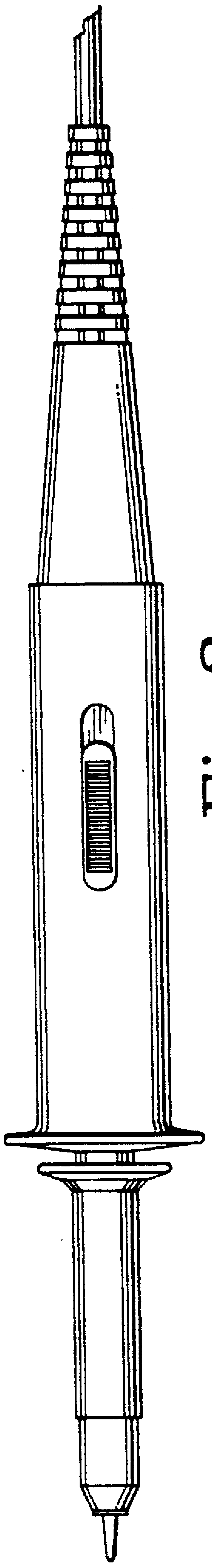


Fig. 3

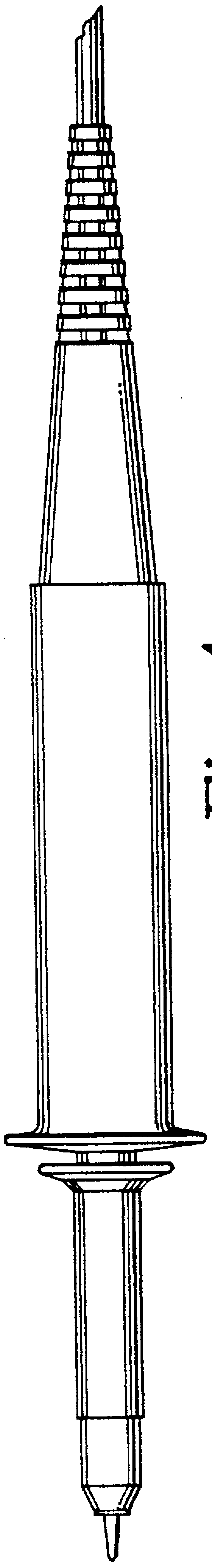


Fig. 4

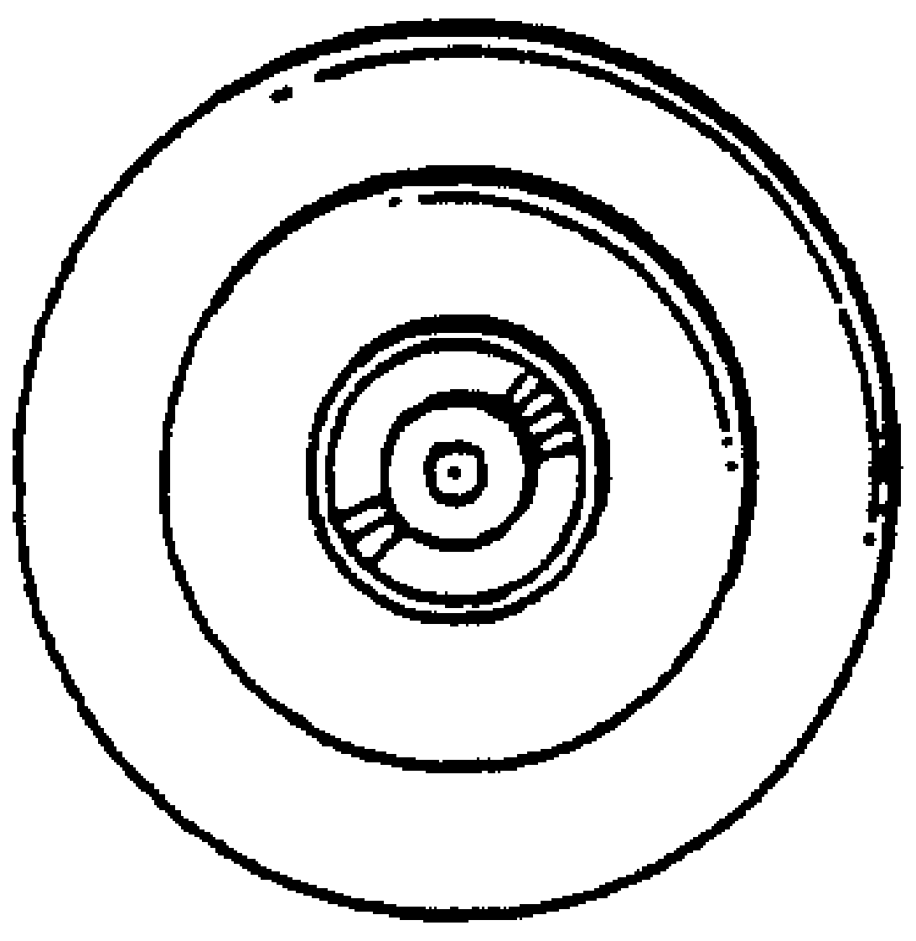


Fig. 5

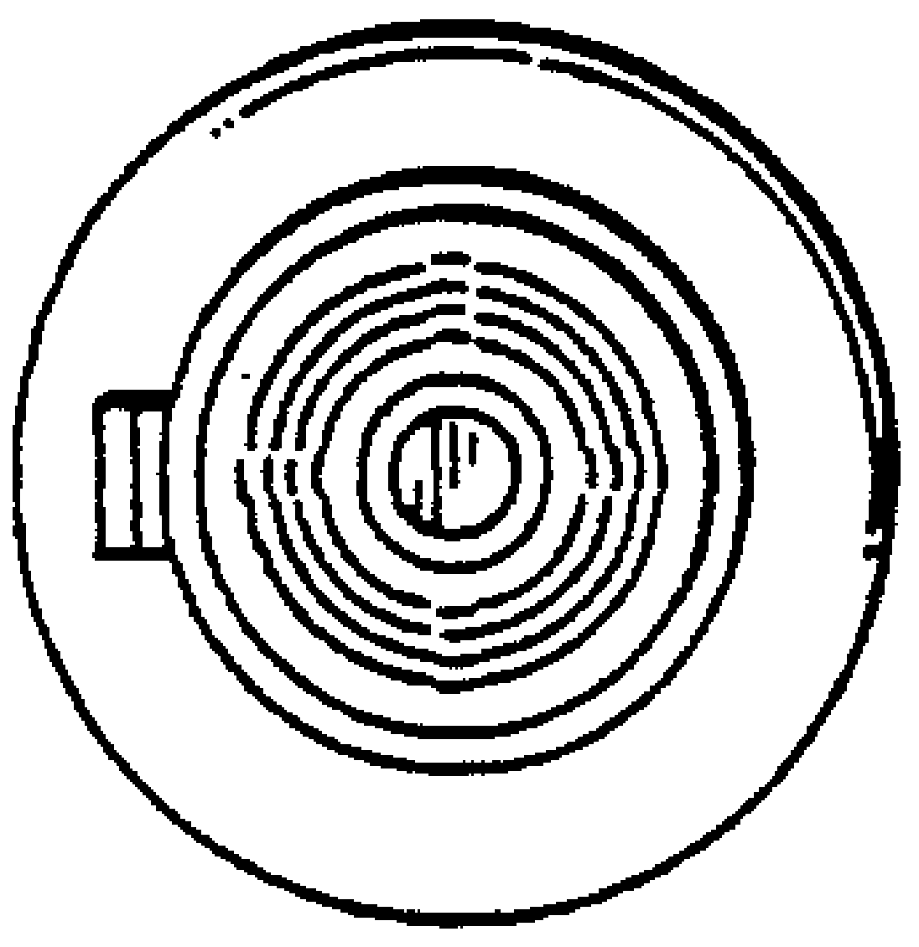


Fig. 6